

RF Devices and RF Circuit Design for Digital Communication

Agenda

- Fundamentals of RF Circuits
- Transmission Line
- Reflection Coefficient & Smith Chart
- Impedance Matching
- S-matrix Representation
- Amplifiers & Unilateral Gain
- RF Devices
- Digital RF

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- Fundamentals of RF Circuits
 - **Lumped-element** circuits: $\lambda \gg L$, L is a typical length of device.
e.g. $\lambda = 30$ cm for $f = 1$ GHz
 - **Distributed-element** circuits: $\lambda \sim L$
Lead Line becomes a coil and/or capacitance.

Historically **Rayleigh** analyzed an undersea cable based on distributed circuit concept.

→ **Image Impedance and Propagation Constant**

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– Basic distributed element: **Transmission Line**

F-matrix of Transmission Line

$$F = \begin{bmatrix} \cos \theta & jZ_0 \sin \theta \\ j \sin \theta / Z_0 & \cos \theta \end{bmatrix}$$

Z_0 : Characteristic impedance of Transmission Line

θ : Phase delay $(= \beta \ell = \omega \sqrt{\epsilon \mu} \ell = \omega \ell / v)$

ℓ : length

v : velocity

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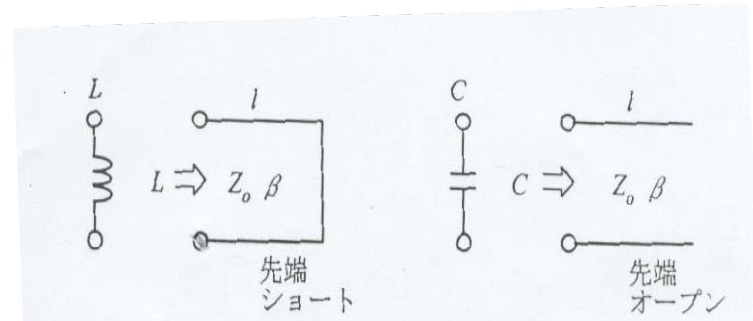
Transmission Line



Inductance, Capacitance,
Filter, Impedance Transformer

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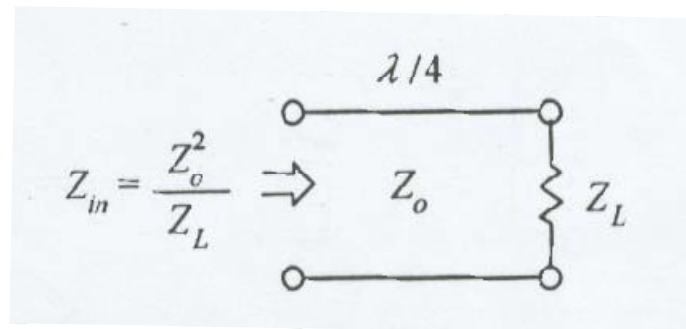
Short-end

Open-end

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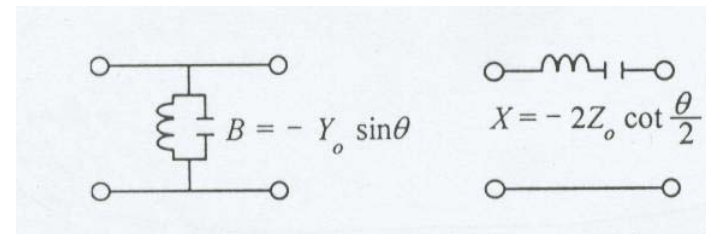
Impedance Inverter : $Z_L \Rightarrow Z_{in}$



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Shunt to Series Connection



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Impedance Matrix of Transmission Line

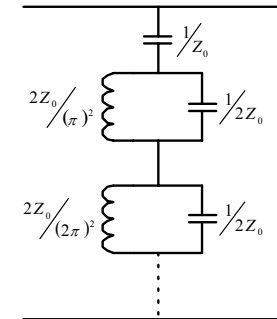
$$Z = \frac{Z_o}{j \sin \theta} \begin{bmatrix} \cos \theta & 1 \\ 1 & \cos \theta \end{bmatrix}$$

$$= \frac{Z_o}{j} \left\{ \frac{1}{\theta} \begin{bmatrix} 1 & 1 \\ 1 & 1 \end{bmatrix} + \sum_{n=1}^{\infty} \frac{2\theta}{\theta^2 - (n\pi)^2} \begin{bmatrix} 1 & (-1)^n \\ (-1)^n & 1 \end{bmatrix} \right\}$$

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Equivalent Circuit of Transmission Line by Foster Expansion



A Series Connection of Parallel Resonance Circuits

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- Short (Open) - circuited load: → **Reactance element**
 $X_{in} = Z_o \tan \theta$: short-circuited load

$0 < \theta < \pi/2$: Inductance

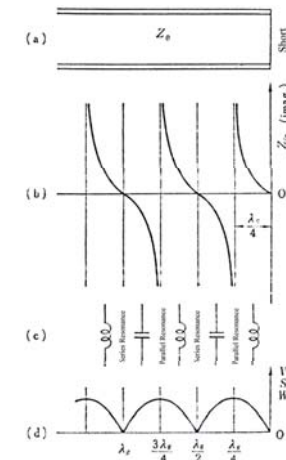
$\theta \approx \pi/2$: Parallel resonance circuit

$\pi/2 < \theta < \pi$: Capacitance

- Stub
- Quarter-wavelength Transformer
- **Matching coating lense**

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Short-terminated Line

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- Reflection coefficient (Γ) and Load Impedance (Z_L)

$$\Gamma = \frac{Z_L - Z_0}{Z_L + Z_0} : \text{Bilinear mapping}$$

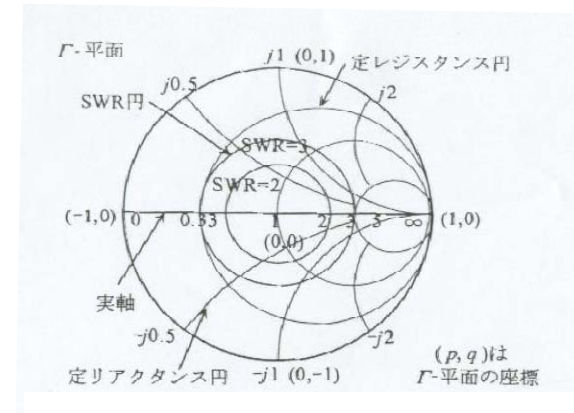
Z_0 : reference characteristic impedance

Circle to Circle Mapping
(Moebius Transform)

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Smith Chart



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$$\text{Re}(Z_L) > 0 : |\Gamma| < 1 \text{ (Passive)}$$

$$\text{Re}(Z_L) = 0 : |\Gamma| = 1 \text{ (Lossless)}$$

Reflection type phase modulator

$$\text{Re}(Z_L) < 0 : |\Gamma| > 1 \text{ (Active)}$$

Reflection type amplifier

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- Voltage Standing Wave Ratio (VSWR) ≥ 1

$$\text{VSWR} = \frac{V_{\max}}{V_{\min}} = \frac{V_i + V_r}{V_i - V_r}$$

$$|\Gamma| = \frac{V_r}{V_i} = \frac{\text{VSWR} - 1}{\text{VSWR} + 1}$$

V_i : incident wave

V_r : reflected wave

- Special Terminations / Circuits

– Matched load: ($Z_L = Z_0$) $\rightarrow \Gamma = 0$, No reflection

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– Smith-chart and its usage

- Smith-chart (Bell Lab. 1950's)

$$Z_{in} = Z_0 \frac{Z_L + jZ_0 \tan \theta}{Z_0 + jZ_L \tan \theta}$$

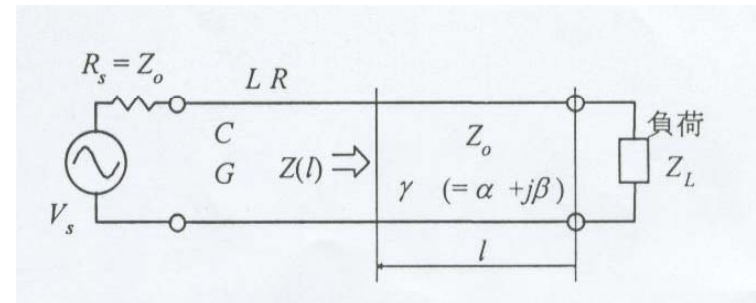
$$Z_L \rightarrow \tilde{Z}_L = \frac{Z_L}{Z_0} \rightarrow \Gamma_L = \frac{\tilde{Z}_L - 1}{\tilde{Z}_L + 1} \rightarrow$$

$$\Gamma_{in} = \Gamma_L \exp^{-j2\theta} \rightarrow \tilde{Z}_{in} = \frac{1 + \Gamma_{in}}{1 - \Gamma_{in}} \rightarrow Z_{in}$$

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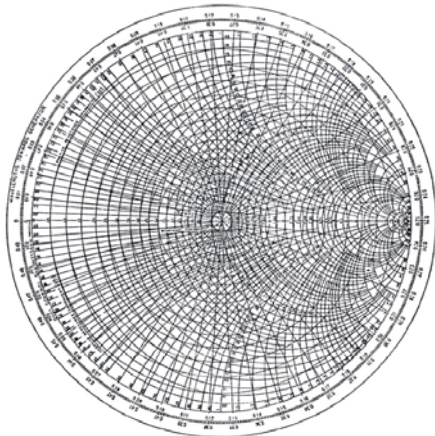
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Impedance Transforming



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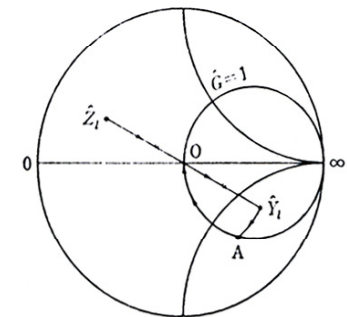
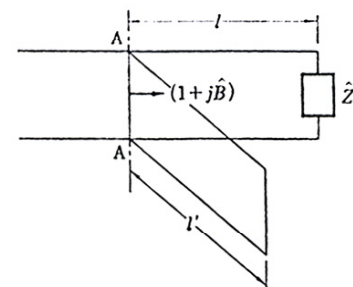


Smith Chart

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- How to use Smith-chart
- Matching Circuit Design



Single-stub Matching

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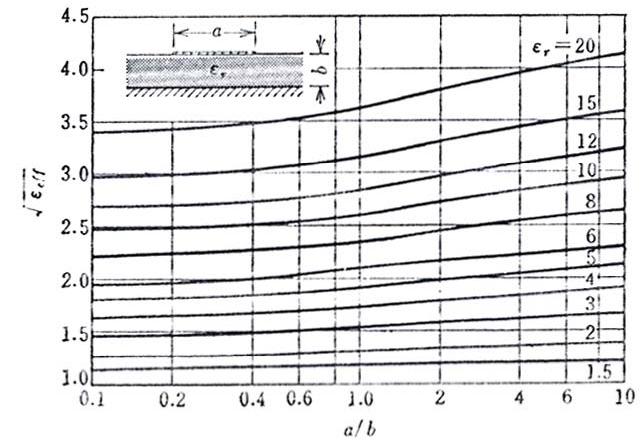
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– Microstrip Line

- Effective permittivity and guided wavelength
- Characteristic Impedance
- Several notes : Finite conductor thickness

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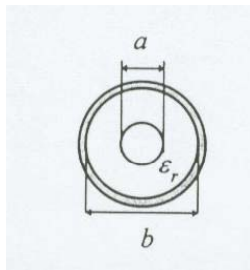
Microstrip Line (Effective Permittivity)

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Coaxial Line

$$Z_0 = \frac{138}{\sqrt{\epsilon_r}} \log \frac{b}{a}$$

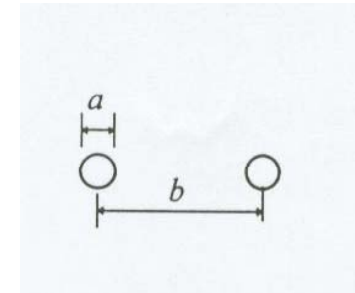


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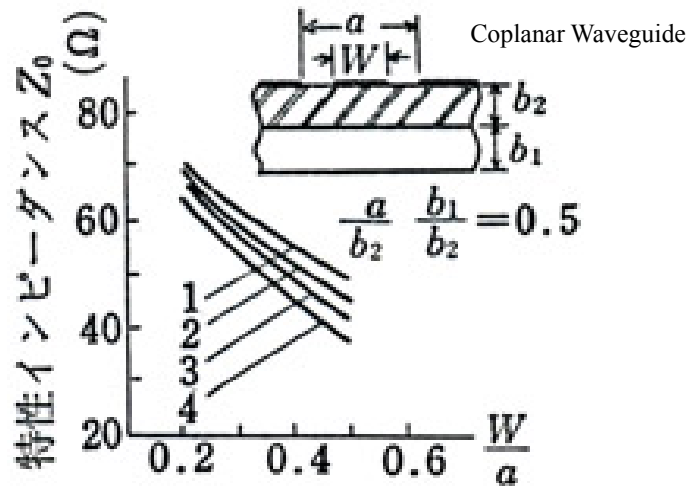
Pair-cable Line

$$Z_0 = 120 \cosh^{-1} \left(\frac{b}{a} \right)$$



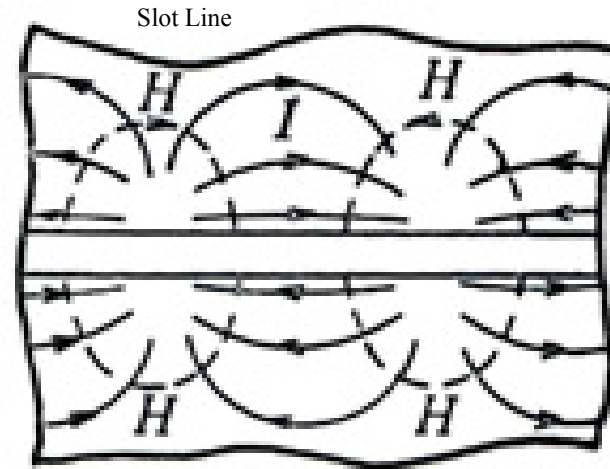
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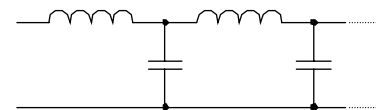
Meta Material

- Right-Hand Transmission Line
- Left-Hand Transmission Line
- Composite RH/LH Transmission Line
- Compact Directional Coupler
- Super-Lense

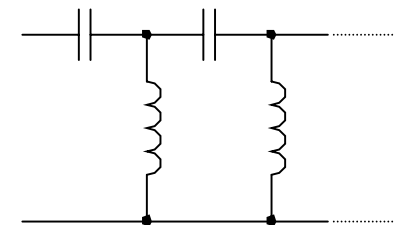
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RHTL

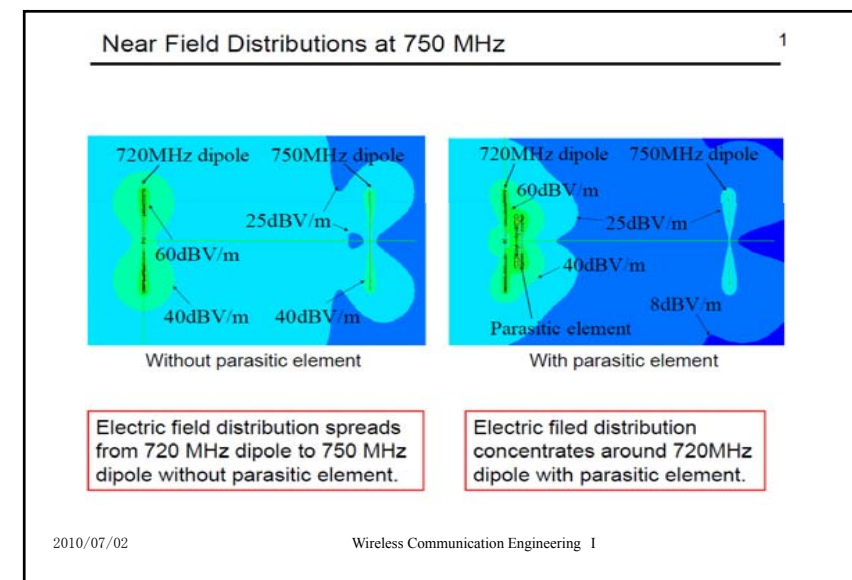
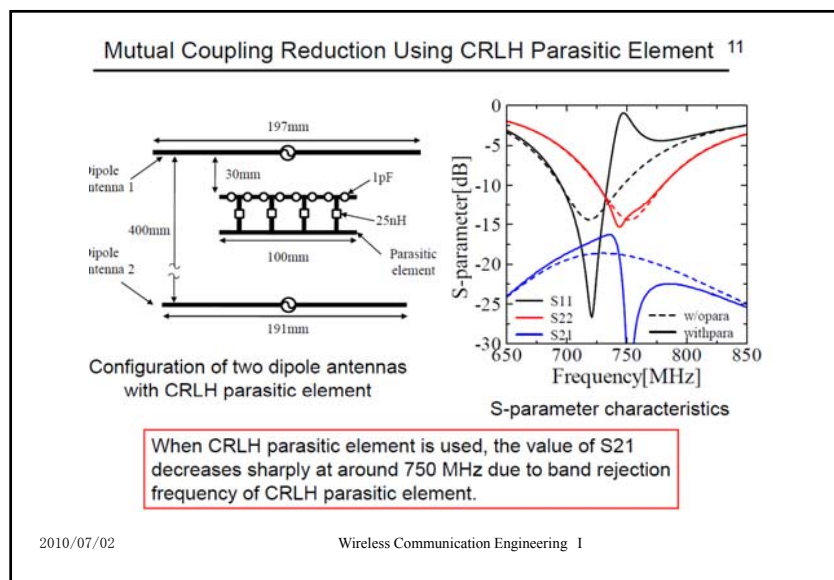
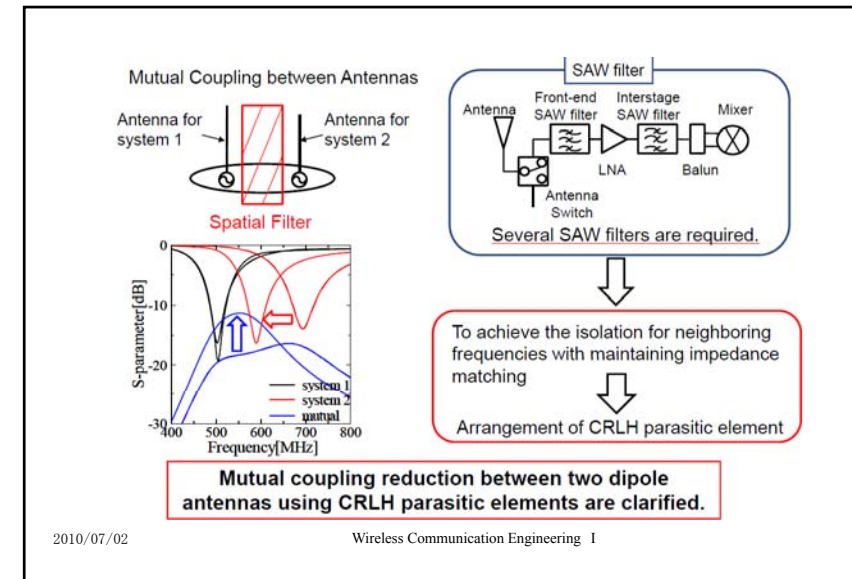
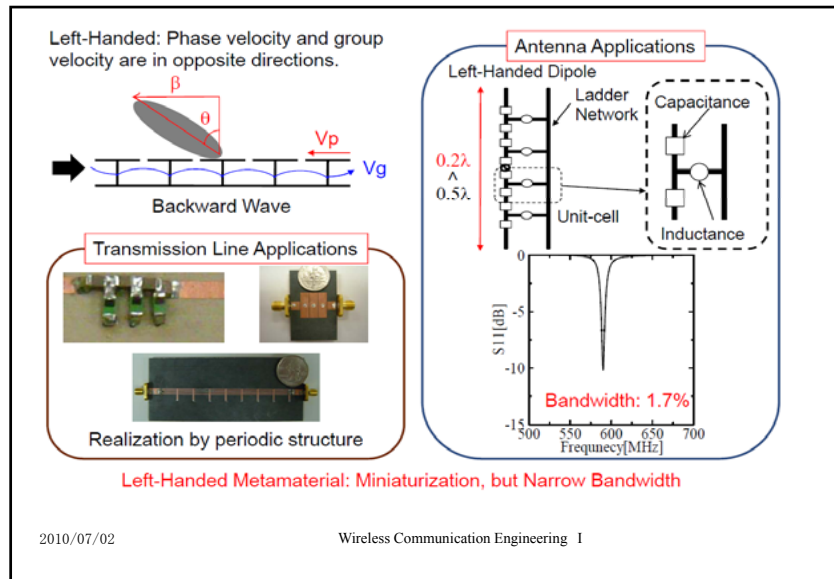


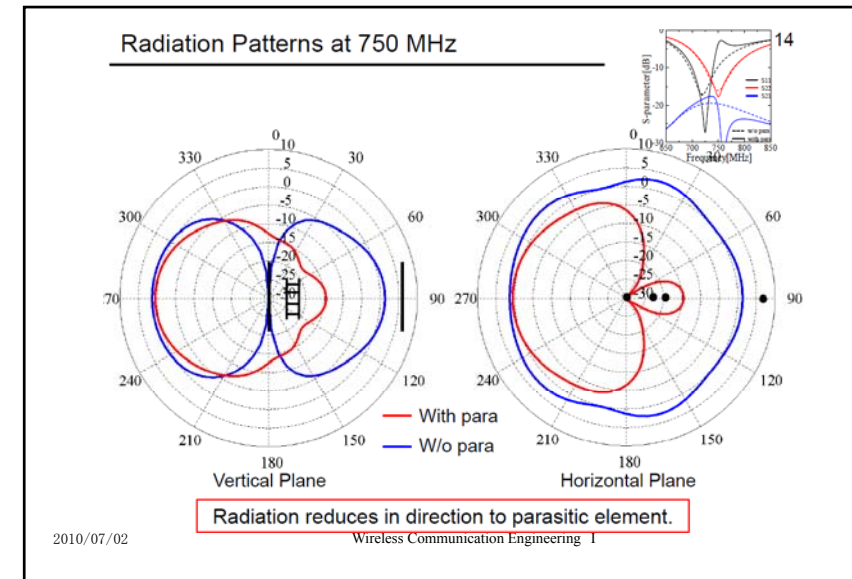
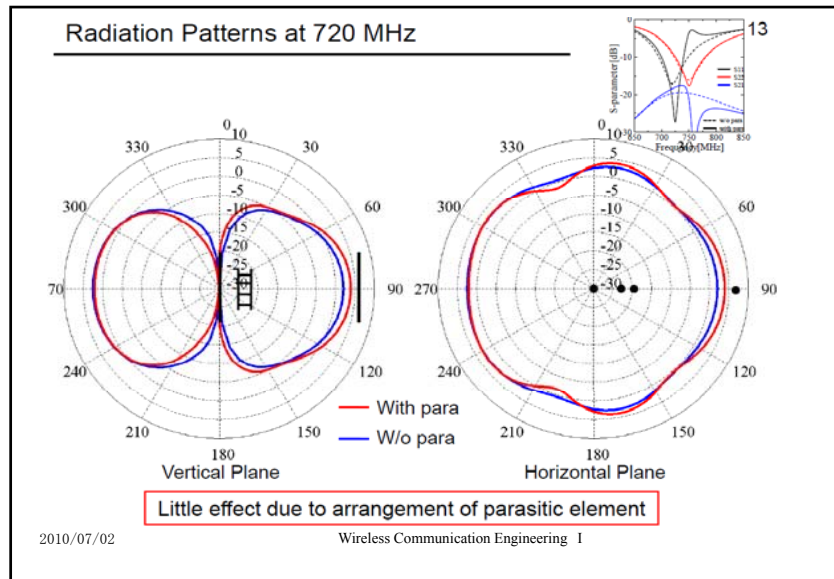
LHTL



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• S-parameter and RF Circuit Design

– S-parameter (1950's ← Nuclear Physics)

voltage, current → incident wave, reflected wave

impedance → reflection coefficient

impedance matrix → scattering matrix, $[S]$

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For **lossless** circuit, **S-matrix** = **Unitary Matrix**

For **lossy** circuit, $S^\dagger S \leq I$ **Para-unitary**

For **Reciprocal** circuit, S-matrix = **Symmetric matrix**

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SVD (Singular Value Decomposition)

$$S = U^\dagger D V \quad (\text{Youla})$$

U, V : Unitary matrix (Lossless Circuit)

D : Diagonal Matrix (\rightarrow Isolated n -port circuit)

$$D = \text{Diag}[\lambda_1, \dots, \lambda_n]$$

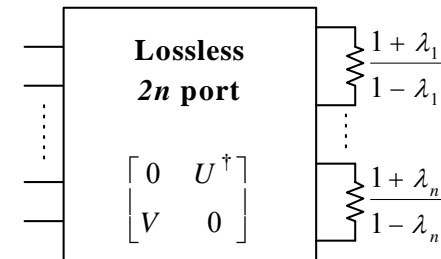
$\lambda_i < 1 \quad \rightarrow$ resistance

$\lambda_i > 1 \quad \rightarrow$ negative resistance

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Generalization of Darlington realization



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– Basics of RF Circuit Design

- Impedance Matching Circuits

$$Z_g = Z_L^*$$

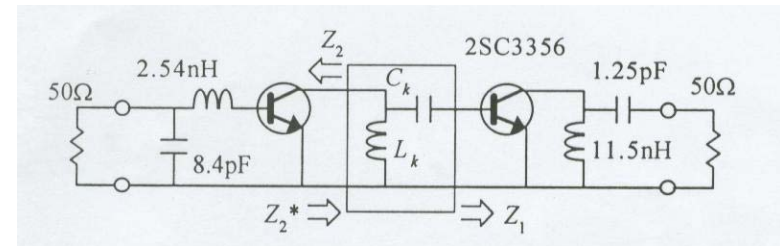
Z_g : Generator Impedance

Z_L : Load Impedance

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Conjugate Matching



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Unilateral Transducer Gain G_{TU}

(For the case, $S_{12} = 0$ Reverse transfer coefficient from output to input)

$$\text{FET } S\text{-parameter} \begin{vmatrix} S_{11} & S_{12} \\ S_{21} & S_{22} \end{vmatrix}$$

$$G_{TU} = \frac{(1 - |\Gamma_s|^2)}{|1 - S_{11}\Gamma_s|^2} \cdot |S_{21}|^2 \cdot \frac{(1 - |\Gamma_L|^2)}{|1 - S_{22}\Gamma_L|^2}$$

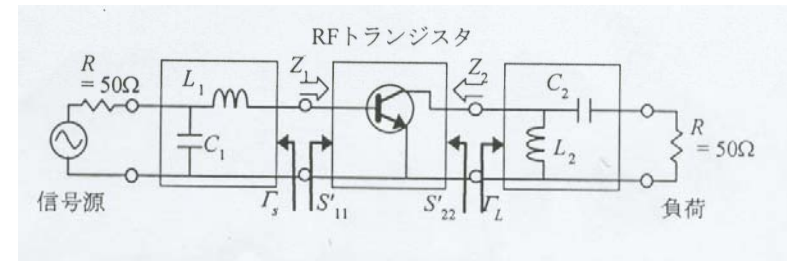
$$= G_s \cdot G_0 \cdot G_L$$

$$G_{TU, \max} = \frac{1}{1 - |S_{11}|^2} \cdot |S_{21}|^2 \cdot \frac{1}{1 - |S_{22}|^2}$$

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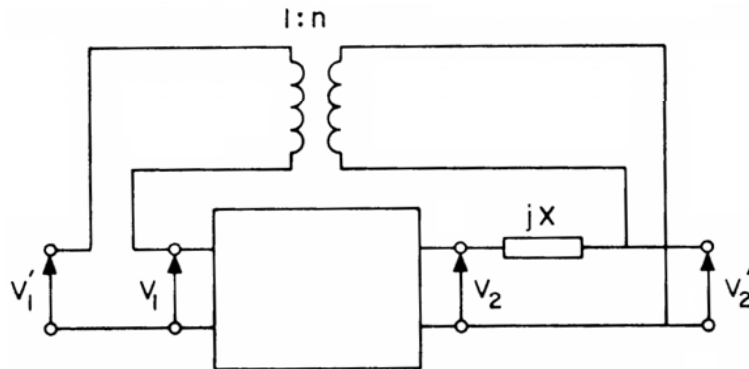
Input and Output Matching Circuit



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Unilateral Gain U : Mason's Invariant



Unilateralization of a two-port network

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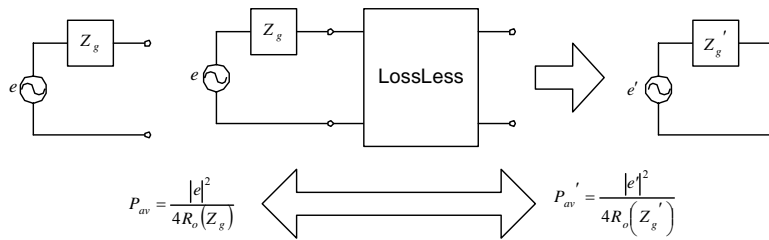
Circuit Invariant

- Unilateral Gain (U)
- Maximum Available Gain (MAG)
- Noise Measure (M)
- 2-state diode (m, Q)
- Circulator Invariant (α)
- Directional Coupler Invariant (K)

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Available Power



2-state device

- On-state impedance Z_1 , Off-state impedance Z_2
- $M = |Z_1 - Z_2| / |Z_1 + Z_2^*| \Rightarrow$ Invariant w.r.t. Lossless 2port connection
- $M = |\Gamma_1 - \Gamma_2| / |1 - \Gamma_1 \Gamma_2^*| \Rightarrow$ Optimum BPSK Direct Modulation Design

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• RF Devices

– Passive Components / Circuits

• Reactance Elements

– Distributed-element:

Open-stub, Short-stub, Line Gap

Wide Line, Narrow Line

– Lumped-element:

Spiral Inductor, Gap Capacitor, Thin Film Capacitor

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Attenuators:

Thin Film Resistor

• Impedance Transformers:

Quarter-wavelength Impedance Transformer

$$Z_{in} = \frac{Z_0^2}{Z_L}$$

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- **Resonator:**

- Lumped Element Type
- Microstrip Line Type
- Dielectric Resonator Type (Good Ceramic)

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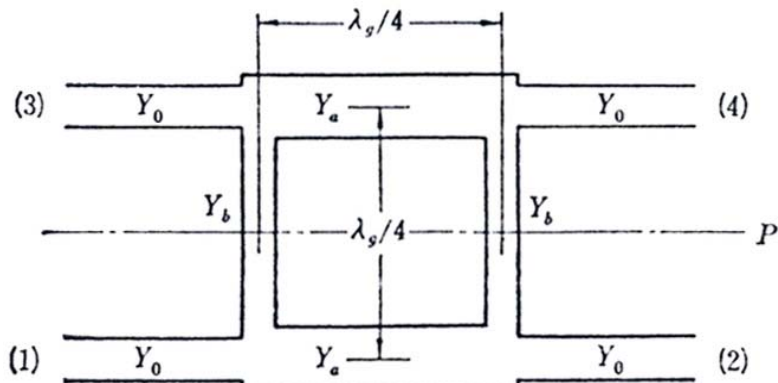
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- **Distributing Components / Circuits**

- Directional Coupler:
 - Power Monitor, Balanced Type Modulator / Amplifier / Mixer
 - Lossless reciprocal matched two-fold symmetry 4-port**
 - **Perfect Directional Coupler with 90deg. Phase Difference**
 - Coupled Line Type
 - Inter-digital Type
 - Branch Line Type
 - Rat-race Type

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Branch-line Coupler

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- **Power Divider / Combiner:**

Perfect Matching + Perfect Isolation → Absorbing Resistance

- **Filter**

- Low Pass Filter (LPF):
 - L, C Ladder Filter
- Band Pass Filter (BPF):
 - Half-wavelength transmission line resonator
- Band Stop Filter (BSF):

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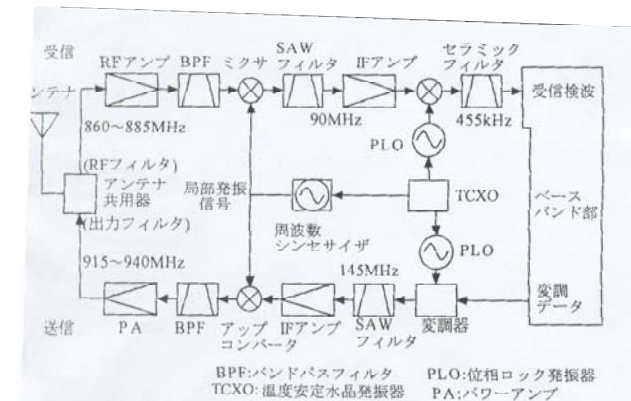
• Transmission Scheme and RF Circuits

Objectives: Low Power Consumption,
Higher Frequency, Small Size,
Low Weight

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Block diagram of Transceiver



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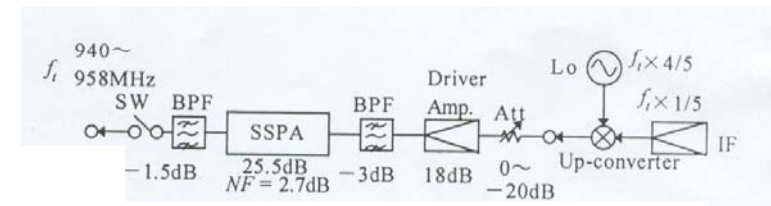
– Basic configuration of RF Circuits: Super-Heterodyne

Mixer: Up-conversion Down-conversion
Amplifier: Power Amp. (TX) Low Noise Amp. (RX)
Oscillator: Local Oscillator
Filter: LPF, BPF

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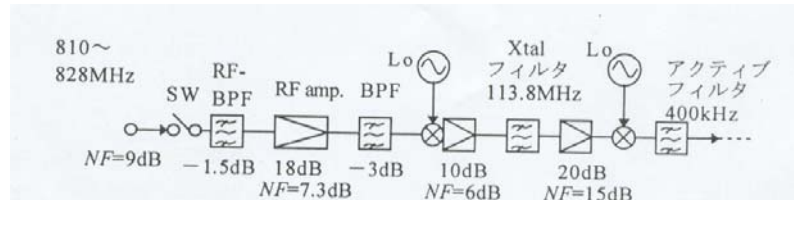
TX Level Diagram



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RX Level Diagram



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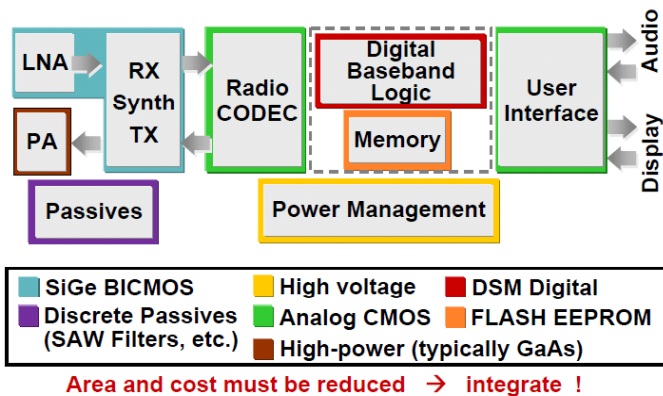
Digital RF Circuits

- RF-CMOS Technology
- Analog Signal Processing & Digital Signal Processing
- Continuous Time & Discrete Time
- Direct Conversion & Sampling
- Built-in RF Self Test & Calibration

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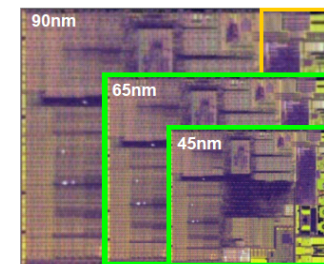
Typical Cell-Phone Block Diagram



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SoC Drives Cost Reduction



◆ SoC Integration Includes:

- ◆ Digital baseband
- ◆ SRAM
- ◆ Power management
- ◆ Analog
- ◆ RF
- ◆ Processors & Software

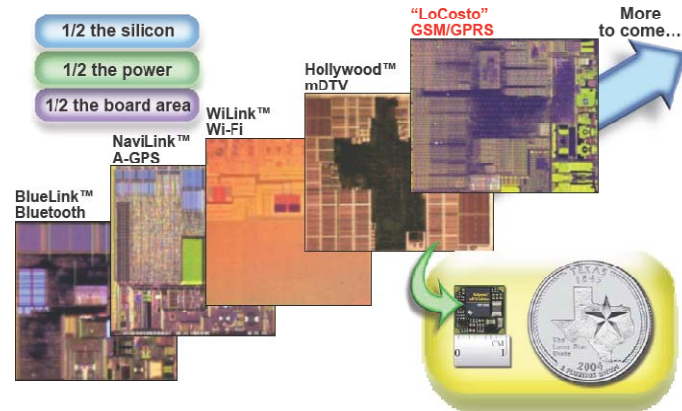
◆ The DRP technology enables digital implementation of traditional analog RF functions in standard CMOS

- ◆ Most advanced process technology used to maximize integration while minimizing cost
 - ◆ 90nm (shipping)
 - ◆ 65nm (mature design)
 - ◆ 45nm and beyond (preliminary)

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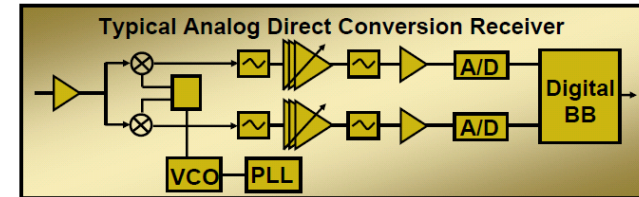
DRP/SoC Proven Across Many Products



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Analog RF Challenges in DSM CMOS

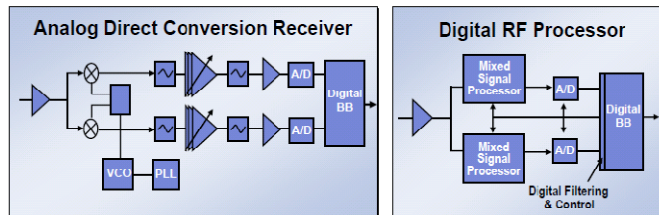


- Power supply voltage overhead – must scale to ~1Volt
- Passives – need high quality inductors, caps, etc.
- Noise/clock coupling – time-align to avoid interference
- Development time – should not delay node migration of digital baseband processor portion.
- Cost – need to minimize multiple pass testing and yield loss

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Digital Transceiver Architecture

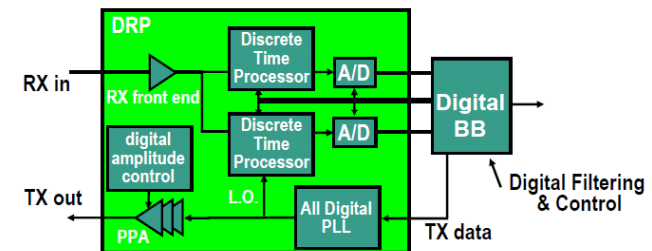


Conventional Direct Conversion is a Great Technology
... but not well suited for CMOS integration
... and digital techniques improve perf/power
... and digital provides a path to SDR!!

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The DRP Approach for Transceivers

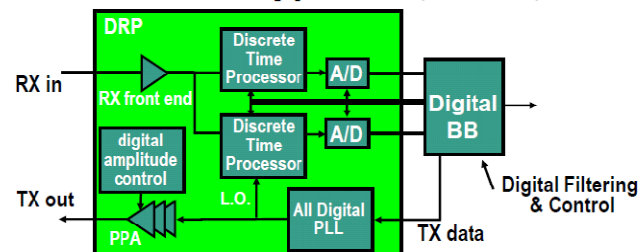


- Minimize analog and RF circuitry**
 - Self-calibrate remaining analog (with dedicated processor)
 - Relax passive requirements as much as possible
- Digital approach speeds debug and development**
- Self-test and calibration made possible**
- Production yield dominated by silicon defect density**

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The DRP Approach (continued)

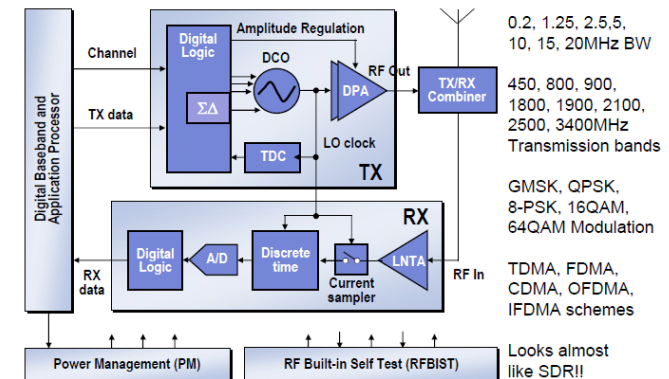


- Move functions to domains of CMOS-process strengths
 - Operate in fine time resolution, avoid fine voltage resolution
 - Inductor area could be equal to ~100K gates (use digital!)
 - Use switched cap techniques – excellent matching in DSM CMOS (not sensitive to process variations)
 - Logic and switched cap circuits can work well at low voltage

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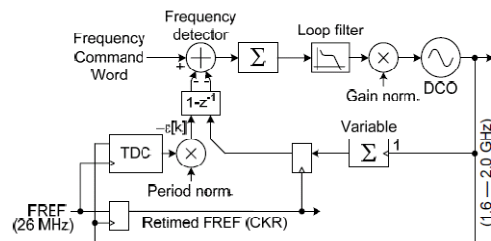
DRP RF Architecture



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All-Digital PLL Vs. Conventional PLL

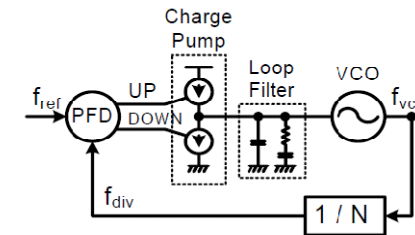


- The ADPLL is "Analog" only in FF, TDC and DCO
- Varactors operate in low sensitivity states ("on" or "off")
- Self-calibration is easy -- DCO gain can be assessed numerically
- Can lock very fast, dynamically change loop bandwidth (<10μsec), and collect register settings for "instant restart" on frequency.

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Drawbacks of Conventional Analog PLL

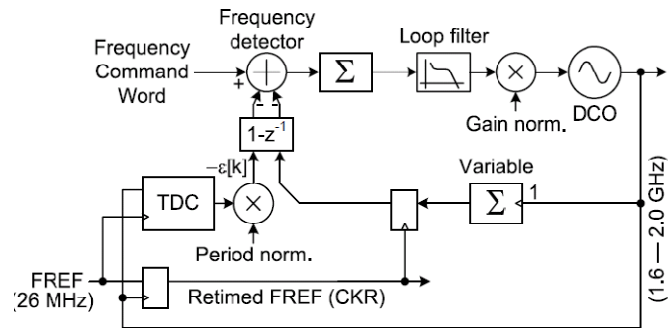


- Many analog functions = multiple noise sources
- Varactors in VCO are sensitive (high tuning factor, i.e. KVCO)
- Loop filter may be large, leaky capacitors (for open loop "freeze"), variances in passives...
- Hard to calibrate
- Lock times can be long (>100μsec)

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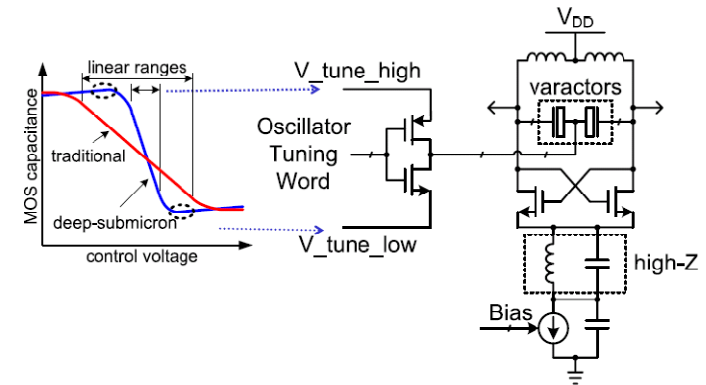
All-Digital PLL (ADPLL)



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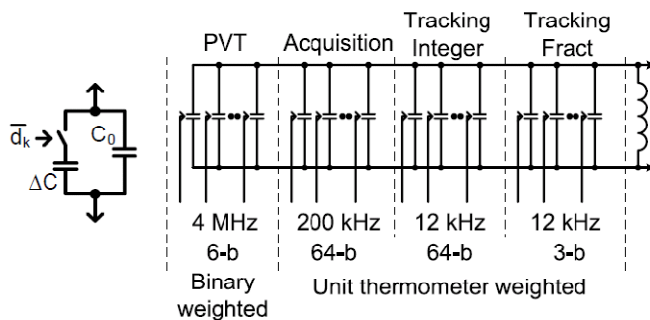
Digitally-Controlled Oscillator Core



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DCO Varactor Banks



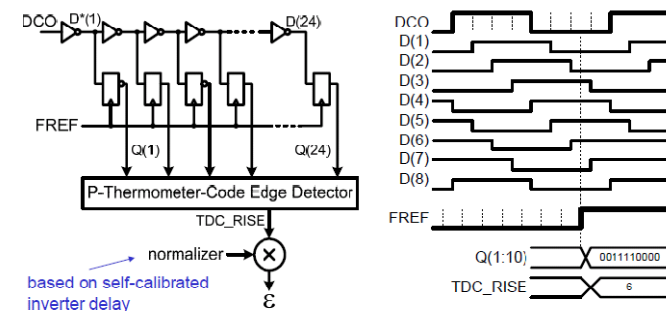
High-speed dithering and dynamic element matching are used to achieve high resolution (LSB = ~1.5Hz).

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Time-to-digital Converter (TDC)

- ◆ Quantized phase detector with resolution of about 20 ps
- ◆ DCO clock passes through the inverter chain
- ◆ Delayed outputs are sampled by FREF

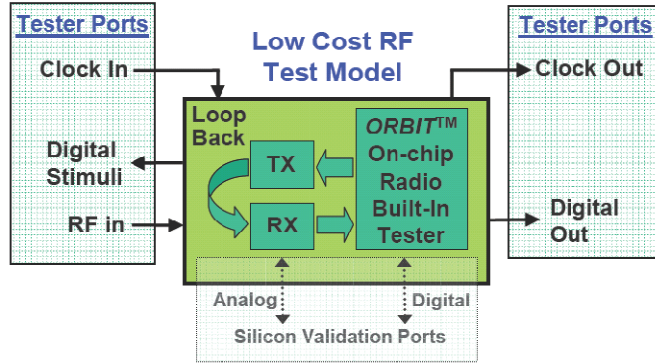


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Wireless Communication Engineering I

Production Testing Simplification

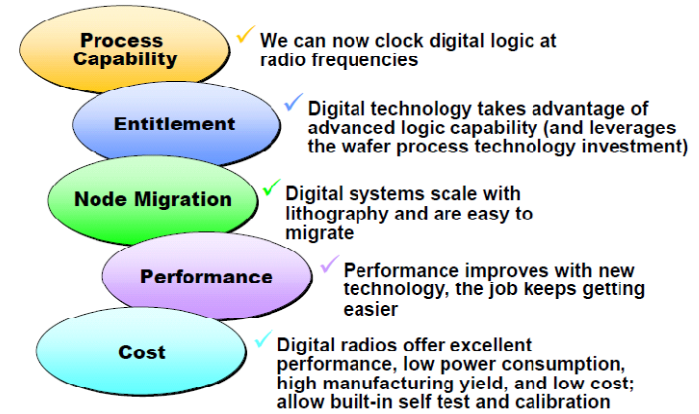
- Extensive use of built-in-testing capabilities to reduce test costs.
- Tester is simple (low cost) and test time is minimal.



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The DRP Technology - Summary



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